

Title (en)

Method and apparatus for supply voltage glitch detection in a monolithic integrated circuit device

Title (de)

Verfahren und Vorrichtung zur Versorgungsspannungs-Störsignaldetektion in einer monolithischen integrierten Schaltungsvorrichtung

Title (fr)

Procédé et appareil de détection de signaux transitoires de tension d'alimentation dans un dispositif à circuit intégré monolithique

Publication

**EP 2982997 A1 20160210 (EN)**

Application

**EP 14179710 A 20140804**

Priority

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Abstract (en)

A monolithic integrated circuit device may include a supply voltage glitch detector (10) for detecting improper supply voltage conditions. Advantageously, the detection threshold of the supply voltage glitch detector is adaptively set based on the mode of operation of the device or a particular part of the device, which is internally known to the device based on certain inputs received by the device, such as commands, interrupts, control signals, and so forth.

IPC 8 full level

**G01R 31/28** (2006.01); **G01R 19/165** (2006.01); **G01R 19/25** (2006.01); **G01R 19/30** (2006.01); **G01R 31/30** (2006.01); **G01R 31/317** (2006.01)

CPC (source: EP)

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Citation (applicant)

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Designated extension state (EPC)

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